

<b>Notice of References Cited</b>	Application/Control No. 10/659,481	Applicant(s)/Patent Under Reexamination DILLON ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0043600	11-2001	Chatterjee et al.	370/390
*	B	US-2004/0258053	12-2004	Toporek et al.	370/352
*	C	US-2004/0199664	10-2004	Feldman et al.	709/238
*	D	US-2003/0112772	06-2003	Chatterjee et al.	370/316
*	E	US-2005/0198309	09-2005	Li et al.	709/227
*	F	US-2004/0049579	03-2004	lms et al.	709/225
*	G	US-2003/0106025	06-2003	Cho et al.	715/523
*	H	US-2003/0037041	02-2003	Hertz, Frederick S. M.	707/1
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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